

# Olivier Thomas

## List of Publications by Year in Descending Order

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The third column is the impact factor (IF) of the journal, and the fourth column is the number of citations of the article.

232  
papers

3,239  
citations

31  
h-index

45  
g-index

243  
ext. papers

3,524  
ext. citations

3.9  
avg, IF

4.81  
L-index

#	Paper	IF	Citations
232	Time-resolved piezoelectric response in relaxor ferroelectric (Pb <sub>0.88</sub> La <sub>0.12</sub> )(Zr <sub>0.52</sub> Ti <sub>0.48</sub> )O <sub>3</sub> thin films. <i>Journal of Applied Physics</i> , <b>2022</b> , 131, 064102	2.5	0
231	Simultaneous Multi-Bragg Peak Coherent X-ray Diffraction Imaging. <i>Crystals</i> , <b>2021</b> , 11, 312	2.3	0
230	Facet-Dependent Strain Determination in Electrochemically Synthesized Platinum Model Catalytic Nanoparticles. <i>Small</i> , <b>2021</b> , 17, e2007702	11	4
229	Crystallization behavior of N-doped Ge-rich GST thin films and nanostructures: An in-situ synchrotron X-ray diffraction study. <i>Microelectronic Engineering</i> , <b>2021</b> , 111573	2.5	2
228	In-situ force measurement during nano-indentation combined with Laue microdiffraction. <i>Nano Select</i> , <b>2021</b> , 2, 99-106	3.1	0
227	Energy-dispersive X-ray micro Laue diffraction on a bent gold nanowire. <i>Journal of Applied Crystallography</i> , <b>2021</b> , 54, 80-86	3.8	1
226	Berkovich nanoindentation study of 16 nm Cu/Nb ARB nanolaminate: Effect of anisotropy on the surface pileup. <i>MRS Advances</i> , <b>2021</b> , 6, 495-499	0.7	2
225	When More Is Less: Plastic Weakening of Single Crystalline Ag Nanoparticles by the Polycrystalline Au Shell. <i>ACS Nano</i> , <b>2021</b> , 15, 14061-14070	16.7	0
224	Twin boundary migration in an individual platinum nanocrystal during catalytic CO oxidation. <i>Nature Communications</i> , <b>2021</b> , 12, 5385	17.4	2
223	In situ measurements of the structure and strain of a $\pi$ -conjugated semiconducting polymer under mechanical load. <i>Journal of Applied Physics</i> , <b>2020</b> , 127, 045108	2.5	4
222	Variable-Wavelength Quick Scanning Nanofocused X-Ray Microscopy for In Situ Strain and Tilt Mapping. <i>Small</i> , <b>2020</b> , 16, e1905990	11	0
221	Multi-wavelength Bragg coherent X-ray diffraction imaging of Au particles. <i>Journal of Applied Crystallography</i> , <b>2020</b> , 53, 170-177	3.8	5
220	New insights into thermomechanical behavior of GeTe thin films during crystallization. <i>Acta Materialia</i> , <b>2020</b> , 191, 60-69	8.4	5
219	Mapping Inversion Domain Boundaries along Single GaN Wires with Bragg Coherent X-ray Imaging. <i>ACS Nano</i> , <b>2020</b> , 14, 10305-10312	16.7	4
218	First stages of plasticity in three-point bent Au nanowires detected by in situ Laue microdiffraction. <i>Applied Physics Letters</i> , <b>2020</b> , 116, 243101	3.4	1
217	Continuous scanning for Bragg coherent X-ray imaging. <i>Scientific Reports</i> , <b>2020</b> , 10, 12760	4.9	4
216	Piezoelectric Properties of PbLa(ZrTi)O Thin Films Studied by In Situ X-ray Diffraction. <i>Materials</i> , <b>2020</b> , 13,	3.5	1

215	Plastic behaviour and deformation mechanisms in silicon nano-objects. <i>Journal of Physics: Conference Series</i> , <b>2019</b> , 1190, 012004	0.3	1
214	In depth characterization of Ge-Si core-shell nanowires using X-ray coherent diffraction and time resolved pump-probe spectroscopy. <i>Journal of Applied Physics</i> , <b>2019</b> , 126, 204304	2.5	0
213	Towards a quantitative determination of strain in Bragg Coherent X-ray Diffraction Imaging: artefacts and sign convention in reconstructions. <i>Scientific Reports</i> , <b>2019</b> , 9, 17357	4.9	15
212	Controlling dislocation nucleation-mediated plasticity in nanostructures via surface modification. <i>Acta Materialia</i> , <b>2019</b> , 166, 572-586	8.4	26
211	In situ structural evolution of single particle model catalysts under ambient pressure reaction conditions. <i>Nanoscale</i> , <b>2018</b> , 11, 331-338	7.7	5
210	Progress of in situ synchrotron X-ray diffraction studies on the mechanical behavior of materials at small scales. <i>Progress in Materials Science</i> , <b>2018</b> , 94, 384-434	42.2	38
209	Crystallographic orientation of facets and planar defects in functional nanostructures elucidated by nano-focused coherent diffractive X-ray imaging. <i>Nanoscale</i> , <b>2018</b> , 10, 4833-4840	7.7	11
208	In situ Bragg coherent X-ray diffraction during tensile testing of an individual Au nanowire. <i>Journal of Applied Crystallography</i> , <b>2018</b> , 51, 781-788	3.8	8
207	Strain Distribution Induced in SOI Photonic Substrate by Through Silicon via Using Advanced Scanning X-Ray Nano-Diffraction. <i>IEEE Transactions on Device and Materials Reliability</i> , <b>2018</b> , 18, 529-533	1.6	0
206	In Situ Coherent X-ray Diffraction during Three-Point Bending of a Au Nanowire: Visualization and Quantification. <i>Quantum Beam Science</i> , <b>2018</b> , 2, 24	1.6	4
205	Three-point bending behavior of a Au nanowire studied by in-situ Laue micro-diffraction. <i>Journal of Applied Physics</i> , <b>2018</b> , 124, 185104	2.5	4
204	In situ monitoring of stress change in GeTe thin films during thermal annealing and crystallization. <i>Micro and Nano Engineering</i> , <b>2018</b> , 1, 63-67	3.4	6
203	Low-temperature intrinsic plasticity in silicon at small scales. <i>Acta Materialia</i> , <b>2018</b> , 161, 54-60	8.4	19
202	Plasticity in inhomogeneously strained Au nanowires studied by Laue microdiffraction. <i>MRS Advances</i> , <b>2018</b> , 3, 2331-2339	0.7	
201	Evaluation of Alternative Atomistic Models for the Incipient Growth of ZnO by Atomic Layer Deposition. <i>Journal of Electronic Materials</i> , <b>2017</b> , 46, 3512-3517	1.9	5
200	A Complex Interrelationship between Temperature-Dependent Polyquaterthiophene (PQT) Structural and Electrical Properties. <i>Journal of Physical Chemistry C</i> , <b>2017</b> , 121, 23149-23157	3.8	1
199	Reactor for nano-focused x-ray diffraction and imaging under catalytic in situ conditions. <i>Review of Scientific Instruments</i> , <b>2017</b> , 88, 093902	1.7	7
198	3D Imaging of a Dislocation Loop at the Onset of Plasticity in an Indented Nanocrystal. <i>Nano Letters</i> , <b>2017</b> , 17, 6696-6701	11.5	32

197	Piezoelectric response and electrical properties of Pb(Zr <sub>1-x</sub> Ti <sub>x</sub> )O <sub>3</sub> thin films: The role of imprint and composition. <i>Journal of Applied Physics</i> , <b>2017</b> , 122, 164104	2.5	8
196	An Atomistic View of the Incipient Growth of Zinc Oxide Nanolayers. <i>Crystal Growth and Design</i> , <b>2016</b> , 16, 5339-5348	3.5	9
195	X-ray nanodiffraction in forward scattering and Bragg geometry of a single isolated Ag/Au nanowire. <i>Thin Solid Films</i> , <b>2016</b> , 617, 9-13	2.2	
194	Stress buildup during crystallization of thin chalcogenide films for memory applications: In situ combination of synchrotron X-Ray diffraction and wafer curvature measurements. <i>Thin Solid Films</i> , <b>2016</b> , 617, 44-47	2.2	6
193	Evolution of Crystal Structure During the Initial Stages of ZnO Atomic Layer Deposition. <i>Chemistry of Materials</i> , <b>2016</b> , 28, 592-600	9.6	23
192	In situ X-ray diffraction studies on the piezoelectric response of PZT thin films. <i>Thin Solid Films</i> , <b>2016</b> , 603, 29-33	2.2	11
191	Temperature dependency of the strain distribution induced by TSVs in silicon: A comparative study between micro-Laue and monochromatic nano-diffraction. <i>Microelectronic Engineering</i> , <b>2016</b> , 156, 59-64	2.5	1
190	KB scanning of X-ray beam for Laue microdiffraction on accelero-phobic samples: application to in situ mechanically loaded nanowires. <i>Journal of Synchrotron Radiation</i> , <b>2016</b> , 23, 1395-1400	2.4	9
189	Spatiotemporal Imaging of the Acoustic Field Emitted by a Single Copper Nanowire. <i>Nano Letters</i> , <b>2016</b> , 16, 6592-6598	11.5	21
188	bending of an Au nanowire monitored by micro Laue diffraction. <i>Journal of Applied Crystallography</i> , <b>2015</b> , 48, 291-296	3.8	31
187	Strain and tilt mapping in silicon around copper filled TSVs using advanced X-ray nano-diffraction. <i>Microelectronic Engineering</i> , <b>2015</b> , 137, 117-123	2.5	12
186	Thermo-mechanical characterization of passive stress sensors in Si interposer. <i>Microelectronics Reliability</i> , <b>2015</b> , 55, 738-746	1.2	0
185	Through-silicon via-induced strain distribution in silicon interposer. <i>Applied Physics Letters</i> , <b>2015</b> , 106, 141905	3.4	9
184	Inversion Domain Boundaries in GaN Wires Revealed by Coherent Bragg Imaging. <i>ACS Nano</i> , <b>2015</b> , 9, 9210-6	16.7	54
183	Continuous and Collective Grain Rotation in Nanoscale Thin Films during Silicidation. <i>Physical Review Letters</i> , <b>2015</b> , 115, 266101	7.4	8
182	New insights into single-grain mechanical behavior from temperature-dependent 3-D coherent X-ray diffraction. <i>Acta Materialia</i> , <b>2014</b> , 78, 46-55	8.4	14
181	Silicide formation during reaction between Ni ultra-thin films and Si(001) substrates. <i>Materials Letters</i> , <b>2014</b> , 116, 139-142	3.3	8
180	In situ coupling of atomic force microscopy and sub-micrometer focused X-ray techniques. <i>Materials Research Society Symposia Proceedings</i> , <b>2014</b> , 1712, 63		1

179	Scanning force microscope for in situ nanofocused X-ray diffraction studies. <i>Journal of Synchrotron Radiation</i> , <b>2014</b> , 21, 1128-33	2.4	27
178	First stage of CoSi <sub>2</sub> formation during a solid-state reaction. <i>Journal of Applied Physics</i> , <b>2014</b> , 116, 245301-5	2.5	5
177	Direct Observation of Gigahertz Coherent Guided Acoustic Phonons in Free-Standing Single Copper Nanowires. <i>Journal of Physical Chemistry Letters</i> , <b>2014</b> , 5, 4100-4	6.4	24
176	Retrieval of the atomic displacements in the crystal from the coherent X-ray diffraction pattern. <i>Journal of Synchrotron Radiation</i> , <b>2014</b> , 21, 774-83	2.4	20
175	Fast pole figure acquisition using area detectors at the DiffAbs beamline ESRF Synchrotron SOLEIL. Erratum. <i>Journal of Applied Crystallography</i> , <b>2014</b> , 47, 482-482	3.8	6
174	Anomalous coherent diffraction of core-shell nano-objects: A methodology for determination of composition and strain fields. <i>Physical Review B</i> , <b>2013</b> , 87,	3.3	6
173	Exploring PdSi(001) and PdSi(111) thin-film reactions by simultaneous synchrotron X-ray diffraction and substrate curvature measurements. <i>Thin Solid Films</i> , <b>2013</b> , 530, 100-104	2.2	8
172	Combined coherent x-ray micro-diffraction and local mechanical loading on copper nanocrystals. <i>Journal of Physics: Conference Series</i> , <b>2013</b> , 425, 132003	0.3	4
171	In situ coherent X-ray diffraction of isolated core-shell nanowires. <i>Thin Solid Films</i> , <b>2013</b> , 530, 113-119	2.2	8
170	CoSi <sub>2</sub> ultra-thin layer formation kinetics and texture from X-ray diffraction. <i>Thin Solid Films</i> , <b>2013</b> , 541, 17-20	2.2	1
169	Decreasing reaction rate at the end of silicidation: In-situ CoSi <sub>2</sub> XRD study and modeling. <i>Microelectronic Engineering</i> , <b>2013</b> , 106, 125-128	2.5	2
168	Strain inhomogeneity in copper islands probed by coherent X-ray diffraction. <i>Thin Solid Films</i> , <b>2013</b> , 530, 120-124	2.2	9
167	Concentration and strain fields inside a Ag/Au core-shell nanowire studied by coherent X-ray diffraction. <i>Nano Letters</i> , <b>2013</b> , 13, 1883-9	11.5	21
166	Fast pole figure acquisition using area detectors at the DiffAbs beamline ESRF Synchrotron SOLEIL. <i>Journal of Applied Crystallography</i> , <b>2013</b> , 46, 1842-1853	3.8	37
165	Comparative study of metallic silicide-germanide orthorhombic MnP systems. <i>Journal of Physics Condensed Matter</i> , <b>2013</b> , 25, 355403	1.8	2
164	Vibrational response of free standing single copper nanowire through transient reflectivity microscopy. <i>Journal of Applied Physics</i> , <b>2013</b> , 114, 193509	2.5	25
163	Thermo-mechanical study of a 2.5D passive silicon interposer technology: Experimental, numerical and In-Situ stress sensors developments <b>2013</b> ,		2
162	In situ combined synchrotron X-ray diffraction and wafer curvature measurements during formation of thin palladium silicide film on Si(001) and Si (111). <i>Nuclear Instruments &amp; Methods in Physics Research B</i> , <b>2012</b> , 284, 74-77	1.2	5

161	Local strain induced in silicon by Si <sub>3</sub> N <sub>4</sub> lines: Modeling and experimental investigation via X-ray diffraction. <i>Nuclear Instruments &amp; Methods in Physics Research B</i> , <b>2012</b> , 284, 23-28	1.2	3
160	In situ three-dimensional reciprocal-space mapping during mechanical deformation. <i>Journal of Synchrotron Radiation</i> , <b>2012</b> , 19, 688-94	2.4	23
159	Thermoelasticity and interdiffusion in CuNi multilayers. <i>Physical Review B</i> , <b>2012</b> , 85,	3.3	7
158	Expected and unexpected plastic behavior at the micron scale: An in situ $\mu$ raue tensile study. <i>Acta Materialia</i> , <b>2012</b> , 60, 1252-1258	8.4	31
157	First-principles study of nickel-silicides ordered phases. <i>Journal of Alloys and Compounds</i> , <b>2011</b> , 509, 2639-2644	3.7	41
156	Nanometer scale assessment of mechanical strain induced in silicon by a periodic line array. <i>Journal of Nanoscience and Nanotechnology</i> , <b>2011</b> , 11, 9160-6	1.3	1
155	Dislocation storage in single slip-oriented Cu micro-tensile samples: new insights via X-ray microdiffraction. <i>Philosophical Magazine</i> , <b>2011</b> , 91, 1256-1264	1.6	37
154	Lattice instabilities in hexagonal NiSi: A NiAs prototype structure. <i>Physical Review B</i> , <b>2010</b> , 81,	3.3	4
153	Methodology for studying strain inhomogeneities in polycrystalline thin films during in situ thermal loading using coherent x-ray diffraction. <i>New Journal of Physics</i> , <b>2010</b> , 12, 035018	2.9	24
152	3D strain imaging in sub-micrometer crystals using cross-reciprocal space measurements: Numerical feasibility and experimental methodology. <i>Nuclear Instruments &amp; Methods in Physics Research B</i> , <b>2010</b> , 268, 388-393	1.2	5
151	Post Si(C)N hillock nucleation and growth in IC copper lines controlled by diffusional creep. <i>Microelectronic Engineering</i> , <b>2010</b> , 87, 361-364	2.5	4
150	X-ray microbeam strain investigation on CuMEMS structures. <i>Microelectronic Engineering</i> , <b>2010</b> , 87, 394-397	3.7	7
149	Nickel silicide encroachment formation and characterization. <i>Microelectronic Engineering</i> , <b>2010</b> , 87, 245-248	3.9	29
148	Out-of-plane stresses arising from grain interactions in textured thin films. <i>Acta Materialia</i> , <b>2010</b> , 58, 2452-2463	8.4	13
147	Finite element simulations of coherent diffraction in elastoplastic polycrystalline aggregates. <i>Comptes Rendus Physique</i> , <b>2010</b> , 11, 293-303	1.4	4
146	Relation between strain and composition in coherent epitaxial Cu/Ni multilayers: Influence of strong concentration gradients. <i>Physical Review B</i> , <b>2009</b> , 79,	3.3	2
145	High-resolution X-ray diffraction as a tool to investigate the evolution of local stress in sub-micrometric Si lines isolated by periodic arrays of oxide-filled trenches. <i>Materials Science in Semiconductor Processing</i> , <b>2009</b> , 12, 64-70	4.3	1
144	First-principles study of the structural, electronic, vibrational, and elastic properties of orthorhombic NiSi. <i>Physical Review B</i> , <b>2009</b> , 79,	3.3	159

143	Diffraction analysis of elastic strains in micro and nanostructures. <i>Zeitschrift für Kristallographie</i> , <b>2008</b> , 223, 569-574		4
142	Applicability of an iterative inversion algorithm to the diffraction patterns from inhomogeneously strained crystals. <i>Physical Review B</i> , <b>2008</b> , 78,	3.3	31
141	Self-aligned nickel-platinum silicide oxidation. <i>Materials Science and Engineering B: Solid-State Materials for Advanced Technology</i> , <b>2008</b> , 154-155, 155-158	3.1	5
140	Texture and strain in narrow copper damascene interconnect lines: An X-ray diffraction analysis. <i>Microelectronic Engineering</i> , <b>2008</b> , 85, 2175-2178	2.5	4
139	Local strains induced in silicon channel by a periodic array of nitride capped poly lines investigated by high resolution X-ray diffraction. <i>Materials Science and Engineering B: Solid-State Materials for Advanced Technology</i> , <b>2008</b> , 154-155, 129-132	3.1	2
138	Influence of crystallographic orientation on local strains in silicon: A combined high-resolution X-ray diffraction and finite element modelling investigation. <i>Thin Solid Films</i> , <b>2008</b> , 516, 8042-8048	2.2	7
137	Nitrogen impurity effects on nickel silicide formation at low temperatures [New Nitrogen co-plasma] approach. <i>Microelectronic Engineering</i> , <b>2008</b> , 85, 2005-2008	2.5	6
136	Local strain in a 3D nano-crystal revealed by 2D coherent X-ray diffraction imaging. <i>Thin Solid Films</i> , <b>2007</b> , 515, 5557-5562	2.2	9
135	Impact of surface preparation on nickel-platinum alloy silicide phase formation. <i>Microelectronic Engineering</i> , <b>2007</b> , 84, 2523-2527	2.5	13
134	Investigation by High Resolution X-ray Diffraction of the local strains induced in Si by periodic arrays of oxide filled trenches. <i>Physica Status Solidi (A) Applications and Materials Science</i> , <b>2007</b> , 204, 2542-2547 <sup>1,6</sup>		12
133	Strain field in silicon on insulator lines using high resolution x-ray diffraction. <i>Applied Physics Letters</i> , <b>2007</b> , 90, 111914	3.4	38
132	Inversion of the diffraction pattern from an inhomogeneously strained crystal using an iterative algorithm. <i>Physical Review B</i> , <b>2007</b> , 76,	3.3	65
131	Investigating Interdiffusion in Mo/V Multilayers from X-Ray Scattering and Kinetic Simulations. <i>Defect and Diffusion Forum</i> , <b>2007</b> , 264, 13-18	0.7	1
130	X-ray scattering: A powerful probe of lattice strain in materials with small dimensions. <i>Applied Surface Science</i> , <b>2006</b> , 253, 182-187	6.7	7
129	Stresses in Copper Damascene Lines: In-situ Measurements and Finite Element Analysis. <i>AIP Conference Proceedings</i> , <b>2006</b> ,	0	5
128	Diffraction from Periodic Arrays of Oxide-Filled Trenches in Silicon: Investigation of Local Strains. <i>Materials Research Society Symposia Proceedings</i> , <b>2006</b> , 913, 1		5
127	Residual stress analysis in micro- and nano-structured materials by X-ray diffraction. <i>International Journal of Materials and Product Technology</i> , <b>2006</b> , 26, 354	1	7
126	Numerical modeling of stress build up during nickel silicidation under anisothermal annealing. <i>Materials Science and Engineering B: Solid-State Materials for Advanced Technology</i> , <b>2006</b> , 135, 95-102	3.1	5



125	Combined synchrotron x-ray diffraction and wafer curvature measurements during NiSi reactive film formation. <i>Applied Physics Letters</i> , <b>2005</b> , 87, 041904	3.4	36
124	Stress Development during the Reactive Formation of Silicide Films. <i>Defect and Diffusion Forum</i> , <b>2005</b> , 237-240, 801-812	0.7	7
123	Mechanical characterization of low-k and barrier dielectric thin films. <i>Microelectronic Engineering</i> , <b>2005</b> , 82, 368-373	2.5	26
122	Pipe-diffusion ripening of Si precipitates in Al-0.5%Cu-1%Si thin films. <i>Philosophical Magazine</i> , <b>2005</b> , 85, 3541-3552	1.6	7
121	Stress Development and Relaxation during Reaction of a Cobalt Film with a Silicon Substrate. <i>Defect and Diffusion Forum</i> , <b>2005</b> , 237-240, 518-523	0.7	2
120	Investigation of local stress fields: Finite element modelling and High Resolution X-Ray Diffraction. <i>Materials Research Society Symposia Proceedings</i> , <b>2005</b> , 875, 1		6
119	Simulation et détermination par rayons X des contraintes dans des micro-composants modélisés. <i>European Physical Journal Special Topics</i> , <b>2004</b> , 118, 109-115		
118	X-ray scattering: A wonderful tool to probe lattice strains in materials with small dimensions. <i>Materials Research Society Symposia Proceedings</i> , <b>2004</b> , 840, Q3.2.1		
117	Stresses and interfacial structure in Au/Ni and Ag/Cu metallic multilayers. <i>Scripta Materialia</i> , <b>2004</b> , 50, 717-721	5.6	13
116	Exploring NiSi thin-film reactions by means of simultaneous synchrotron X-Ray diffraction and substrate curvature measurements. <i>Materials Science and Engineering B: Solid-State Materials for Advanced Technology</i> , <b>2004</b> , 114-115, 67-71	3.1	11
115	In situ study of stress evolution during the reaction of a nickel film with a silicon substrate. <i>Microelectronic Engineering</i> , <b>2004</b> , 76, 318-323	2.5	21
114	In situ stress measurements during the growth at different temperatures of Ag/Cu(111) multilayers. <i>Journal of Applied Physics</i> , <b>2004</b> , 95, 1152-1161	2.5	4
113	Stresses and Interfacial Structure in Metal Films and Multilayers of Nanometre Thickness. <i>Journal of Metastable and Nanocrystalline Materials</i> , <b>2004</b> , 19, 129-152	0.2	1
112	Impact of thermal cycling on the evolution of grain, precipitate and dislocation structure in Al, 0.5% Cu, 1% Si thin films. <i>Microelectronic Engineering</i> , <b>2003</b> , 70, 447-454	2.5	7
111	Simulation of local mechanical stresses in lines on substrate. <i>Microelectronic Engineering</i> , <b>2003</b> , 70, 455-469	4.9	7
110	First stages of silicidation in Ti/Si thin films. <i>Microelectronic Engineering</i> , <b>2003</b> , 70, 166-173	2.5	4
109	In-situ study of stress evolution during solid state reaction of Pd with Si(001) using synchrotron radiation. <i>Microelectronic Engineering</i> , <b>2003</b> , 70, 436-441	2.5	6
108	X-ray diffraction from inhomogeneous thin films of nanometre thickness: modelling and experiment. <i>Journal of Applied Crystallography</i> , <b>2003</b> , 36, 154-157	3.8	7



107	Stresses arising from a solid state reaction between palladium films and Si(001) investigated by in situ combined x-ray diffraction and curvature measurements. <i>Journal of Applied Physics</i> , <b>2003</b> , 94, 1584-1591	2.5	31
106	Influence of Si substrate orientation on stress development in Pd silicide films grown by solid-state reaction. <i>Applied Physics Letters</i> , <b>2003</b> , 83, 1334-1336	3.4	19
105	The early stages of stress development during epitaxial growth of Ag/Cu multilayers. <i>Materials Research Society Symposia Proceedings</i> , <b>2003</b> , 791, 1		
104	Thermal expansion and stress development in the first stages of silicidation in Ti/Si thin films. <i>Journal of Applied Physics</i> , <b>2003</b> , 94, 7083-7090	2.5	8
103	Interplay between anisotropic strain relaxation and uniaxial interface magnetic anisotropy in epitaxial Fe films on (001) GaAs. <i>Physical Review Letters</i> , <b>2003</b> , 90, 017205	7.4	122
102	Cubic local order around Al and intermixing in short-period AlN/TiN multilayers studied by Al K-edge extended x-ray absorption fine structure spectroscopy and x-ray diffraction. <i>Applied Physics Letters</i> , <b>2003</b> , 82, 3659-3661	3.4	13
101	Stresses in Multilayer Systems: Test of the sin <sup>2</sup> ψ Method. <i>Advanced Engineering Materials</i> , <b>2002</b> , 4, 557-561	3.5	1
100	Chemically diffuse interface in (1 1 1) Au/Ni multilayers: an anomalous X-ray diffraction analysis. <i>Applied Surface Science</i> , <b>2002</b> , 188, 110-114	6.7	5
99	Microstructural analysis of AU/NI multilayers interfaces by SAXS and STM. <i>Applied Surface Science</i> , <b>2002</b> , 188, 182-187	6.7	11
98	In situ study of strain evolution during thin film Ti/Al(Si,Cu) reaction using synchrotron radiation. <i>Microelectronic Engineering</i> , <b>2002</b> , 64, 81-89	2.5	2
97	Influence of segregation on the measurement of stress in thin films. <i>Journal of Applied Physics</i> , <b>2002</b> , 91, 2951-2958	2.5	8
96	Interfacial structure in (111) Au:Ni multilayers investigated by anomalous x-ray diffraction. <i>Physical Review B</i> , <b>2001</b> , 64,	3.3	32
95	Stress evolution in a Ti/Al(Si,Cu) dual layer during annealing. <i>Materials Research Society Symposia Proceedings</i> , <b>2001</b> , 673, 1		1
94	X-Ray Diffraction Analysis and Modeling of Strain Induced Thermal Cycling in a Thin Aluminum (011) Bicrystal Film. <i>Materials Research Society Symposia Proceedings</i> , <b>2001</b> , 695, 1		1
93	In Situ Stress and Strain Measurements During the Growth of Cu/Ni (001) Multilayers. <i>Materials Research Society Symposia Proceedings</i> , <b>2000</b> , 615, 861		1
92	In Situ Curvature and Diffraction Studies of Pd Films on Si(001) During Solid-State Reaction. <i>Materials Research Society Symposia Proceedings</i> , <b>2000</b> , 615, 831		
91	Chemical vapor deposition of silicon-germanium heterostructures. <i>Journal of Crystal Growth</i> , <b>2000</b> , 216, 171-184	1.6	27
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87	Asymptotic behaviour of stress establishment in thin films. <i>Surface Science</i> , <b>2000</b> , 465, L764-L770	1.8	30
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72	The composition analysis of YBa <sub>2</sub> Cu <sub>3</sub> O <sub>7-<math>\delta</math></sub> /PrBa <sub>2</sub> Cu <sub>3</sub> O <sub>7-<math>\delta</math></sub> thin films and (YBa <sub>2</sub> Cu <sub>3</sub> O <sub>7-<math>\delta</math></sub> ) <sub>1-x</sub> (PrBa <sub>2</sub> Cu <sub>3</sub> O <sub>7-<math>\delta</math></sub> ) <sub>x</sub> heterostructures prepared by CVD. <i>Fresenius Journal of Analytical Chemistry</i> , <b>1997</b> , 357, 1061-1065		2

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63	. <i>IEEE Transactions on Applied Superconductivity</i> , <b>1995</b> , 5, 1737-1740	1.8	17
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57	Texture influence on critical current density of YBCO films deposited on (100)-MgO substrates. <i>Physica C: Superconductivity and Its Applications</i> , <b>1994</b> , 235-240, 627-628	1.3	11
56	Transmission electron microscopy studies of thin films of YBa <sub>2</sub> Cu <sub>3</sub> O <sub>7-x</sub> . <i>Physica C: Superconductivity and Its Applications</i> , <b>1994</b> , 235-240, 655-656	1.3	1
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44	Fundamental and harmonic a.c. susceptibility response of MOCVD YBa <sub>2</sub> Cu <sub>3</sub> O <sub>7</sub> thin films: Model of flux line behaviour. <i>Cryogenics</i> , <b>1993</b> , 33, 497-501	1.8	1
43	Dopant diffusion in silicides: Effect of diffusion paths. <i>Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films</i> , <b>1992</b> , 10, 907-911	2.9	5
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41	In-Situ Preparation of Y-Ba-Cu-O Thin Films Using Mass-Spectrometer Rate Control and Atomic Oxygen. <i>Materials Research Society Symposia Proceedings</i> , <b>1992</b> , 275, 299		1
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24	Analysis of the electrical resistivity of Ti, Mo, Ta, and W monocrystalline disilicides. <i>Journal of Applied Physics</i> , <b>1989</b> , 65, 1584-1590	2.5	40
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21	Some properties of Cr <sub>x</sub> V <sub>1-x</sub> Si <sub>2</sub> and Cr <sub>x</sub> Mo <sub>1-x</sub> Si <sub>2</sub> thin films. <i>Applied Surface Science</i> , <b>1989</b> , 38, 94-105	6.7	4
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